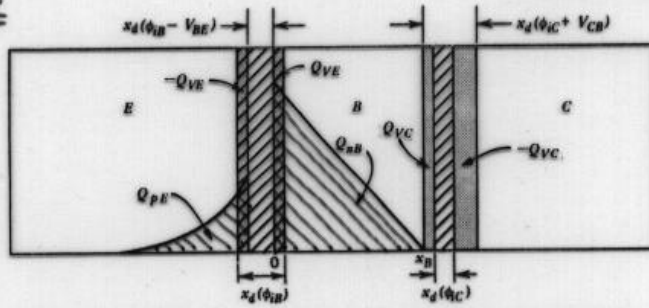


# CHARGE CONTROL MODEL : TIME VARIABLES ARE CONTROLLED CHARGES

INSTEAD OF V AND I

## ACTIVE BIAS



$E \approx$  STEADY STATE

$$I_C = \frac{Q_F}{\tau_F}$$

$$I_B = \frac{Q_F}{\tau_{BF}}$$

$Q_F > 0$  (MAJORITY CH. IN THE BASE)

Figure 7.14 Cross section of a prototype transistor showing the locations of the charge components used in charge-control modeling. The charges  $Q_V$  represent storage at the edges of the space-charge regions. The cross-hatching indicates the two junction space-charge regions at thermal equilibrium.

SET OF LINEAR EQUATIONS

$$Q_F = Q_{NB} + Q_{PE}$$

$$\begin{cases} i_C = \frac{Q_F}{\tau_F} - \frac{d}{dt} Q_{VC} \\ i_B = \frac{Q_F}{\tau_{BF}} + \frac{d}{dt} Q_F + \frac{d}{dt} Q_{VE} + \frac{d}{dt} Q_{VC} \\ i_E = -Q_F \left( \frac{1}{\tau_F} + \frac{1}{\tau_{BF}} \right) - \frac{d}{dt} Q_F - \frac{d}{dt} Q_{VE} \end{cases}$$

~~$\tau_F$  :  $\bar{t}$  TRANSIT TIME~~  
 ~~$\tau_{BF}$  :  $\bar{t}$  LIFE TIME~~

TRANSIENT TERMS ASSOCIATED TO THE VARIATION OF THE SPACE CHARGE

$$\beta_F = \frac{\tau_{BF}}{\tau_F} = \frac{I_C}{I_B}$$

$\tau_F$  AND  $\tau_{BF}$  : OBTAINED FROM MEASUREMENT

$$Q_F = Q_{F0} \left( e^{\frac{qV_{BE}}{kT}} - 1 \right)$$

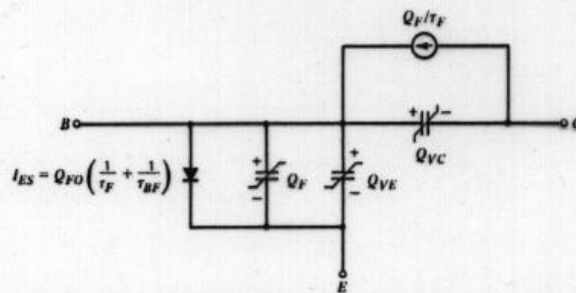
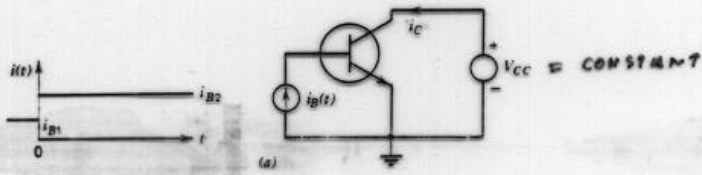


Figure 7.15 Charge-control representation of an npn transistor under active bias with junction-charge storage and injected-base charge taken into account.

BASIC PREMISES FOR CHARGE-CONTROL ANALYSIS:  $\tau_F$  AND  $\tau_{BF}$  INDEPENDENT OF CHARGE AND VOLTAGE.

BUT NOT EXACTLY TRUE FOR SHORT TIME AFTER SWITCHING.

APPLICATIONS: BJT IN F.A.M.



$i_B = \frac{Q_F}{\tau_{BF}} + \frac{dQ_F}{dt}$   
 WHAT IS  $i_C(t)$ ?

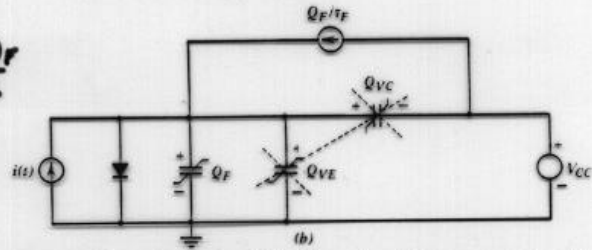


Figure 7.16 (a) Simple circuit for illustration of charge-control model. (b) Equivalent-circuit model. The cancelled elements carry negligible currents.

$i_C = \beta_F [i_{B2} + (i_{B1} - i_{B2}) e^{-t/\tau_{BF}}]$

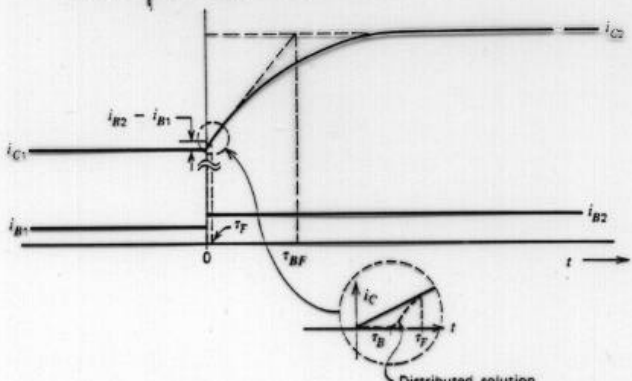
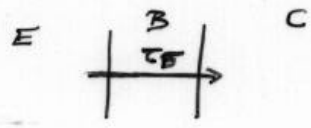


Figure 7.17 Time variation of collector current in the circuit of Figure 7.16 as calculated from the charge-control model.



# LARGE SIGNAL MODEL : SWITCHING: CUT-OFF ↔ SATURATION

$Q_F, Q_R$  : SUPERPOSITION

$$\begin{cases} i_E = -\frac{dQ_F}{dt} - Q_F\left(\frac{1}{\tau_F} + \frac{1}{\tau_{BF}}\right) + \frac{Q_R}{\tau_R} - \frac{dQ_{VE}}{dt} \\ i_C = \frac{Q_F}{\tau_F} - \frac{dQ_R}{dt} - Q_R\left(\frac{1}{\tau_R} + \frac{1}{\tau_{BR}}\right) - \frac{dQ_{VC}}{dt} \\ i_B = \frac{d}{dt}(Q_F + Q_R) + \frac{Q_F}{\tau_{BF}} + \frac{Q_R}{\tau_{BR}} + \frac{d}{dt}(Q_{VE} + Q_{VC}) \end{cases}$$

WITH  $Q_F = Q_{FO} \left( e^{\frac{qV_{BE}}{kT}} - 1 \right)$   
 $Q_R = Q_{RO} \left( e^{\frac{qV_{BC}}{kT}} - 1 \right)$

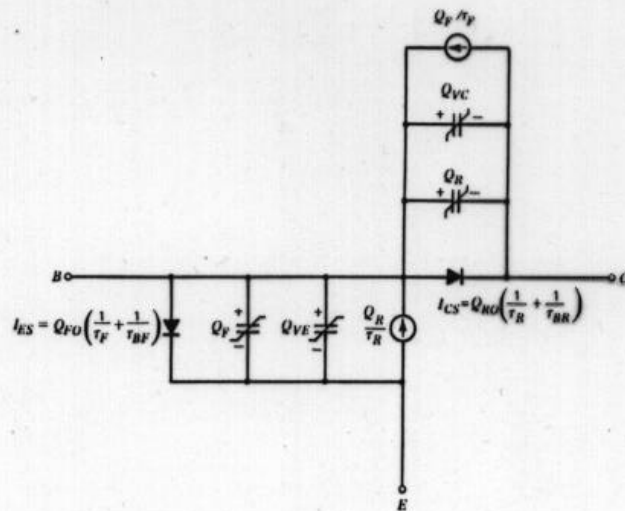
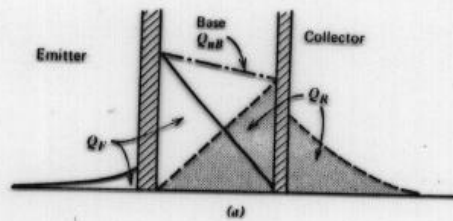


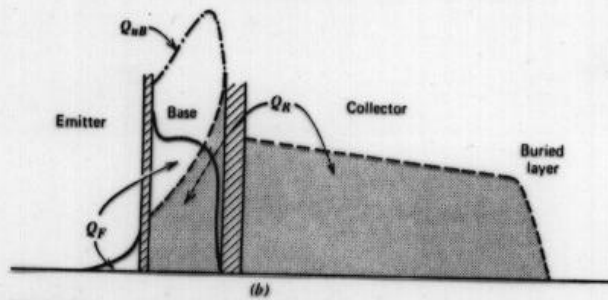
Figure 7.18 Complete bipolar charge-control model for large-signal applications.

$$Q_R = Q_{R0} \left( \exp\left(\frac{qV_{BC}}{kT}\right) - 1 \right) \epsilon$$

SATURATION



HOMOGENEOUS BJT



EPITAXIAL DIFFUSED IC TRANSISTOR

Figure 7.19 The locations of  $Q_F$  and  $Q_R$  (dashed lines) for saturated conditions: (a) in a homogeneously doped transistor with a lightly doped collector region and (b) in an epitaxially diffused IC transistor. The dot-dash lines represent the total base charge  $Q_{nB}$ .

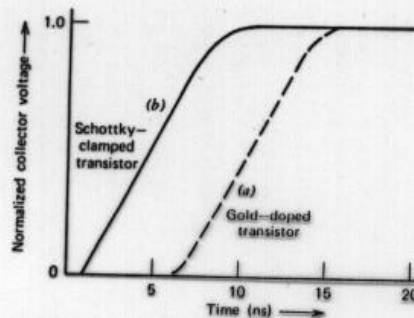


Figure 7.20 Comparison of turn-off times of (a) gold-doped and (b) Schottky-clamped transistors. The gold-doped device is delayed 7 ns for recombination to take place before it begins to change state.<sup>11</sup>